

09A27818

10/604492

Electronic Version

Stylesheet Version v1.1.1

702 M

-24

712512003

2003/0057950

Claims

Prec T 8/19/2003

324/339

[c1] A method for determining a subsurface formation property, comprising:

a determining a volume fraction of a layer in a multi-electrical-layer model for an anisotropic region of the formation, wherein the multi-electrical-layer model includes a relative-lower-resistivity layer and a relative-higher-resistivity layer and the determining is based on a resistivity measurement;

B determining a resistivity for the relative-lower-resistivity layer and a resistivity for the relative-higher-resistivity layer based on the volume fraction and bulk resistivity measurements of the anisotropic region, wherein the bulk resistivity measurements include a horizontal resistivity measurement or a vertical resistivity measurement; and

C determining the formation property based on the volume fraction, the resistivity of the relative-lower-resistivity layer, the resistivity of the relative-higher-resistivity layer, a porosity measurement of the anisotropic region, and the bulk resistivity measurements.

[c2] The method of claim 1, wherein the formation property

is a total water saturation.

- [c3] The method of claim 2, wherein the water saturation is determined according to:

$$S_{wt} = 1 - \frac{\phi_T - [(1 - VF) \sqrt{\frac{R_w}{R_{hr}}} + VF \sqrt{\frac{R_w}{R_{lr}}}]}{\phi_T}$$

wherein  $S_{wt}$  is the total water saturation,  $\phi_T$  is the total porosity of the anisotropic region,  $VF$  is the volume fraction of the relative-lower-resistivity layer,  $R_{hr}$  is the resistivity of the relative-higher-resistivity layer,  $R_{lr}$  is the resistivity of the relative-lower-resistivity layer, and  $R_w$  is a resistivity of formation water.

- [c4] The method of claim 1, wherein the formation property is a bulk hydrocarbon volume.

- [c5] The method of claim 4, wherein the bulk volume of hydrocarbon is determined according to:

$$BVH = \phi_T - [(1 - VF) \sqrt{\frac{R_w}{R_{hr}}} + VF \sqrt{\frac{R_w}{R_{lr}}}]$$

wherein  $BVH$  is the bulk hydrocarbon volume,  $\phi_T$  is the total porosity of the anisotropic region,  $VF$  is the volume fraction of the relative-lower-resistivity layers,  $R_{hr}$  is the resistivity of the relative-higher-resistivity layer,  $R_{lr}$  is

the resistivity of the relative-lower-resistivity layer, and  $R_w$  is a resistivity of formation water.

- [c6] The method of claim 1, wherein the volume fraction is of the relative-lower-resistivity layer.
- [c7] The method of claim 1, wherein the resistivity measurement is a high-resolution measurement.
- [c8] The method of claim 7, wherein the determination of a volume fraction includes identifying bed boundaries based on the high-resolution resistivity measurement.
- [c9] The method of claim 8, wherein identifying the bed boundaries includes finding inflection points on a derivative curve of the high-resolution resistivity measurement as a function of a borehole axial depth.
- [c10] The method of claim 1, wherein the volume fraction is determined by summing thicknesses of thin layers having similar electrical properties.
- [c11] The method of claim 1, wherein determination of the formation property is further based on a dual-water model or NMR data.
- [c12] The method of claim 1, wherein the volume fraction or the formation property is determined within a depth or time index interval.

[c13] A system for determining a subsurface formation property, comprising:

- a computer system adapted to process a program including instructions for: determining a volume fraction of a layer in a multi-electrical-layer model for an anisotropic region of the formation, wherein the multi-electrical-layer model comprises a relative-lower-resistivity layer and a relative-higher-resistivity layer and the determining is based on a resistivity measurement;
- b determining a resistivity for the relative-lower-resistivity layer and a resistivity for the relative-higher-resistivity layer based on the volume fraction and bulk resistivity measurements of the anisotropic region, wherein the bulk resistivity measurements include a horizontal resistivity measurement or a vertical resistivity measurement; and
- c determining the formation property based on the volume fraction, the resistivity of the relative-lower-resistivity layer, the resistivity of the relative-higher-resistivity layer, a porosity measurement of the anisotropic region, and the bulk resistivity measurements.

[c14] The system of claim 13, wherein the formation property is a total water saturation.

- [c15] The system of claim 14, wherein the water saturation is determined according to:

$$S_{\text{wt}} = 1 - \frac{\phi_r - [(1 - VF) \sqrt{\frac{R_w}{R_{\text{hr}}}} + VF \sqrt{\frac{R_w}{R_s}}]}{\phi_r}$$

wherein  $S_{\text{wt}}$  is the total water saturation,  
 $\phi_r$

is the total porosity of the anisotropic region,  $VF$  is the volume fraction of the relative-lower-resistivity layer,  $R_{\text{hr}}$  is the resistivity of the relative-higher-resistivity layer,  $R_s$  is the resistivity of the relative-lower-resistivity layer, and  $R_w$  is a resistivity of formation water.

- [c16] The system of claim 13, wherein the formation property is a bulk hydrocarbon volume.

- [c17] The system of claim 16, wherein the bulk volume of hydrocarbon is determined according to:

$$\text{BVH} = \phi_r - [(1 - VF) \sqrt{\frac{R_w}{R_{\text{hr}}}} + VF \sqrt{\frac{R_w}{R_s}}]$$

wherein  $\text{BVH}$  is the bulk hydrocarbon volume,  
 $\phi_r$

is the total porosity of the anisotropic region,  $VF$  is the volume fraction of the relative-lower-resistivity layer,  $R_{\text{hr}}$

is the resistivity of the relative-higher-resistivity layer,  $R_{lr}$   
is the resistivity of the relative-lower-resistivity layer,  
and  $R_w$  is a resistivity of formation water.

- [c18] The system of claim 13, wherein the volume fraction is of the relative-low-resistivity layer.
- [c19] The system of claim 13, wherein the resistivity measurement is a high-resolution measurement.
- [c20] The system of claim 19, wherein determination of a volume fraction includes identifying bed boundaries based on the high-resolution resistivity measurement.
- [c21] The system of claim 20, wherein identifying the bed boundaries includes finding inflection points on a derivative curve of the high-resolution resistivity measurement as a function of a borehole axial depth.
- [c22] The system of claim 13, wherein the volume fraction is determined by summing thicknesses of thin layers having similar electrical properties.
- [c23] The system of claim 13, wherein determination of the formation property is based on a dual-water model or NMR data.
- [c24] The system of claim 13, wherein the volume fraction or the formation property is determined within a depth or

**time index.**